

The importance of valley splitting in few-electron donor based quantum dots in silicon

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QIST Workshop

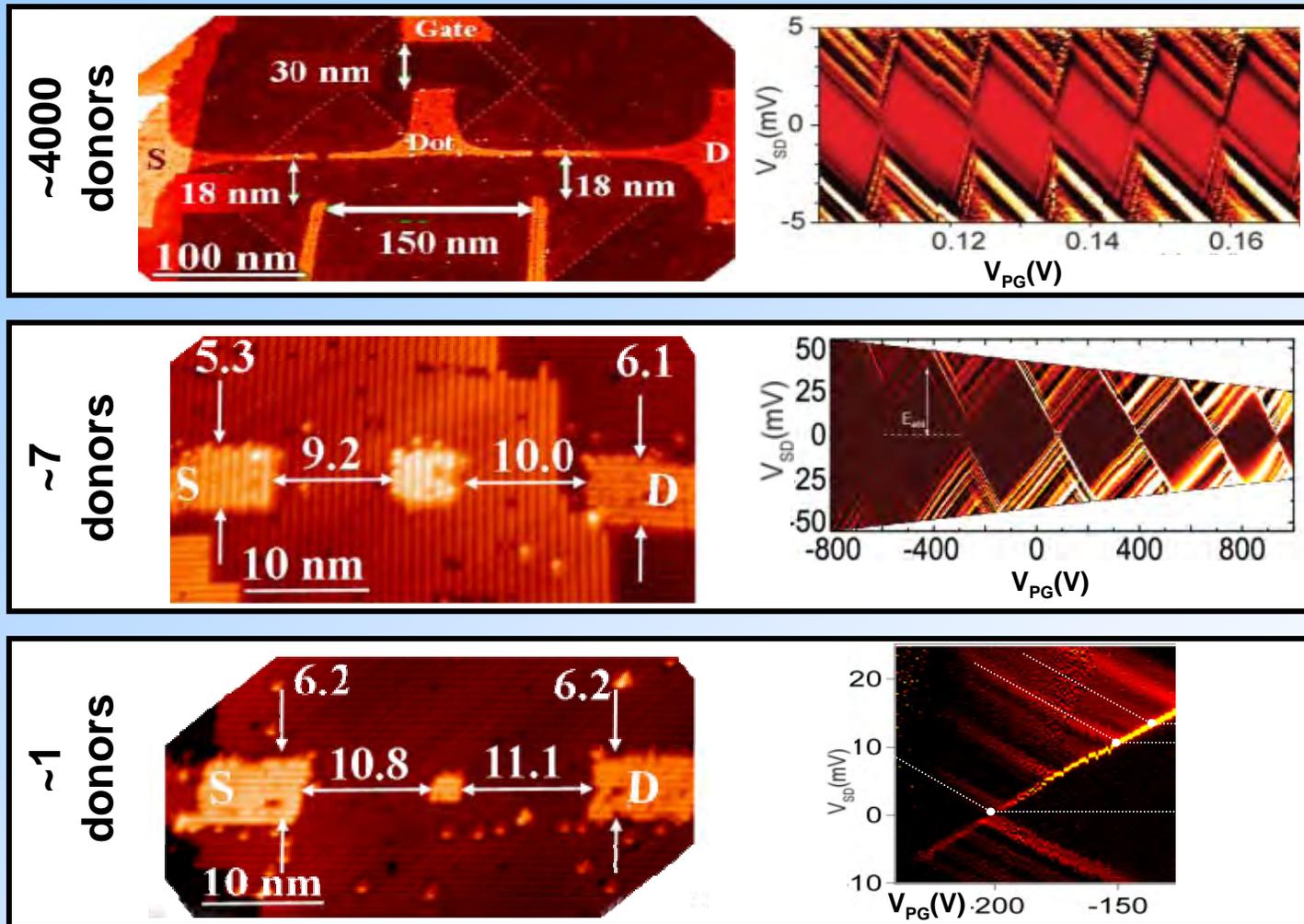
Berkeley, August 2008



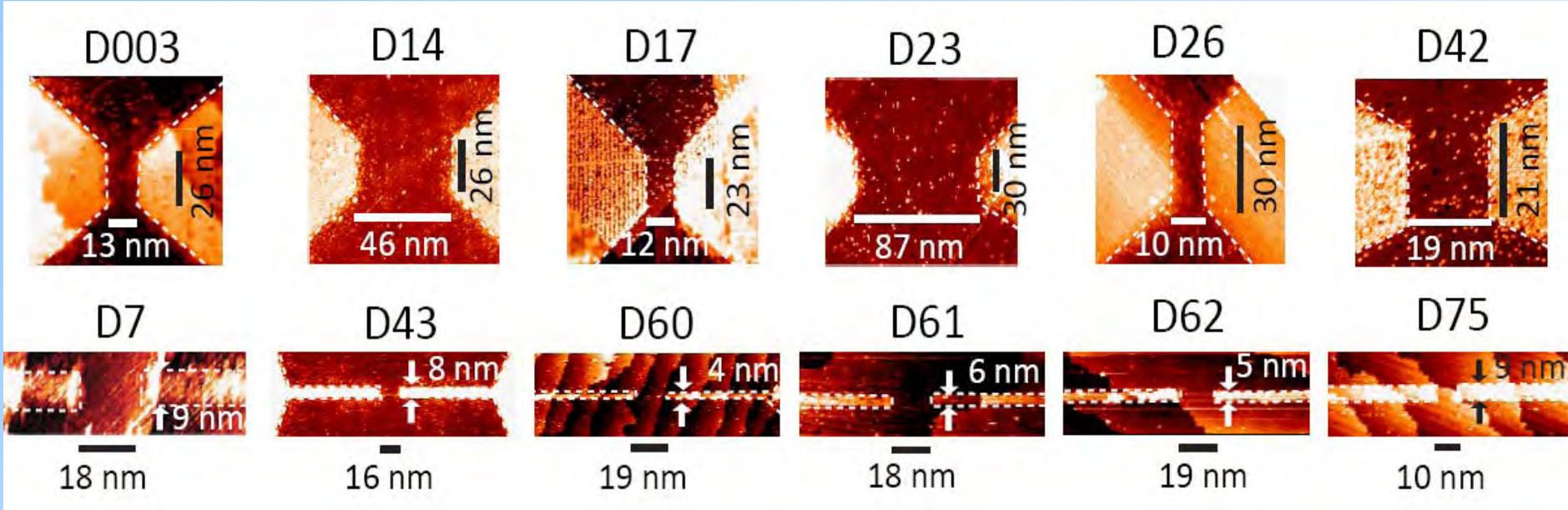
Atomically precise Si:P devices

- STM allows for atomically precise patterning of donor structures
 - Goal: down-scaling to a single P donor
- Decreased number of donors from 4000 to the single donor limit
 - ~7 donor quantum dot: surprisingly dense excitation spectrum observed → can be explained by valley splitting
 - Effective mass calculations: valley splitting of dot states
 - Single donor limit: evidence for excited states of a single P in Si
 - Strategies for charge sensing

STM-patterned Si:P donor based quantum dots



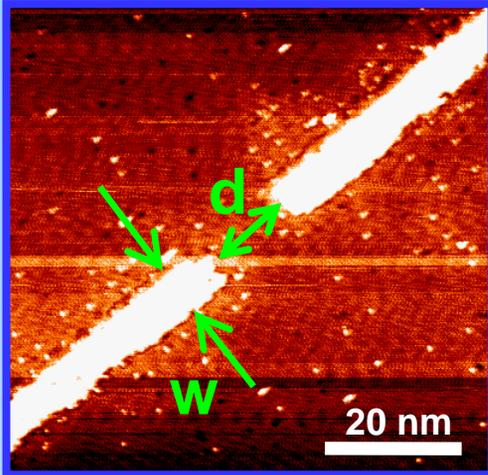
Tailoring the tunneling resistance



- Increased device yield now allows statistical study of device behaviour
- We fabricated a series of tunnel gaps to determine the effect of the gap geometry on the tunnel resistance

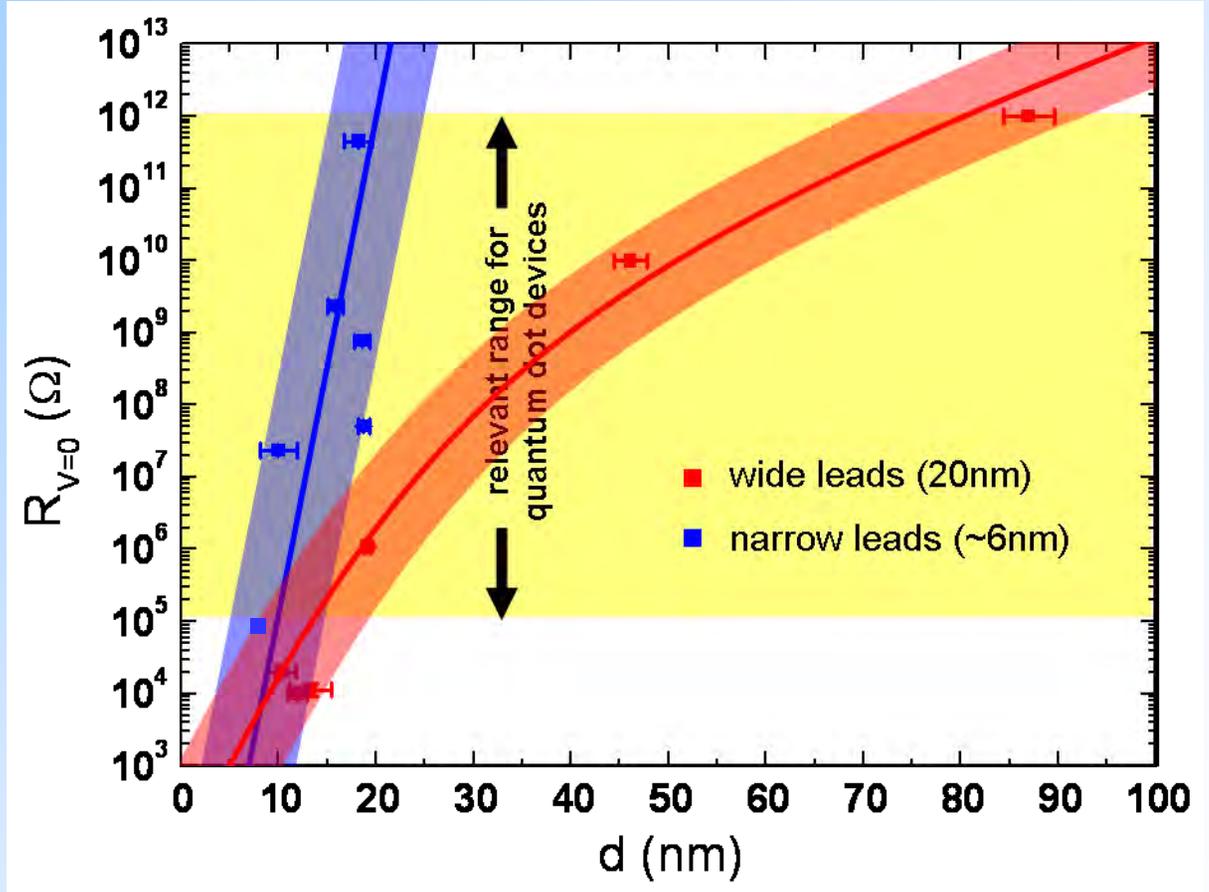
Tailoring the tunneling resistance

tunnel gap device



d = separation

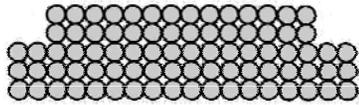
w = lead width



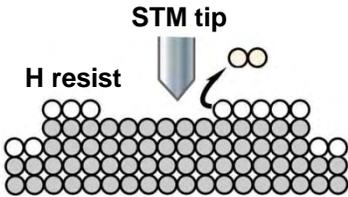
- Gap aspect ratio (w/d) determines transport characteristics
- These results allow us to predict device behaviour and improve device design

STM based fabrication

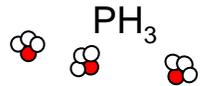
Step-free Si(100) surface



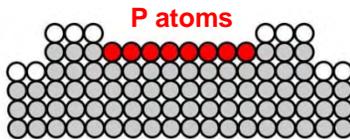
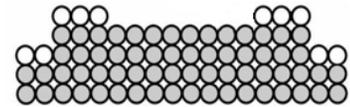
Initial anneal at 1100°C



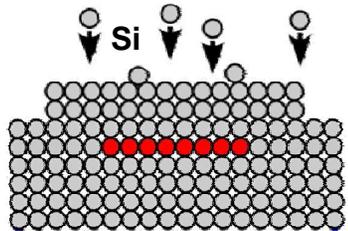
Use STM tip to desorb hydrogen



PH₃ adsorbs onto exposed Si



Incorporate P donors

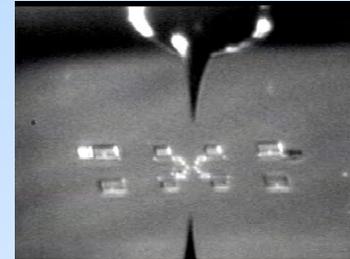


Encapsulation with 25nm of epitaxial Si

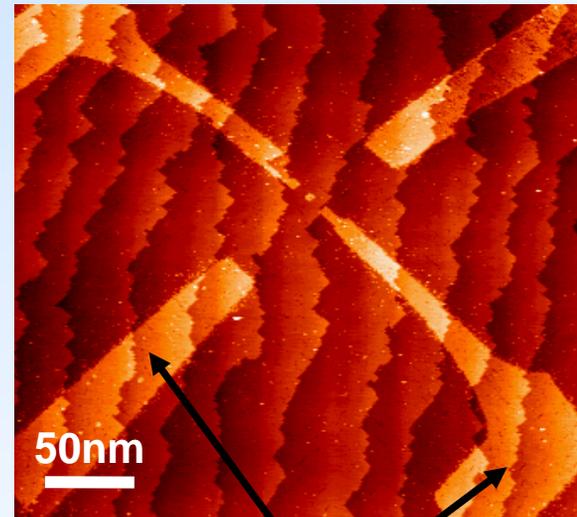
UHV

ex-situ processing: ohmic contacts and top-gates

STM tip

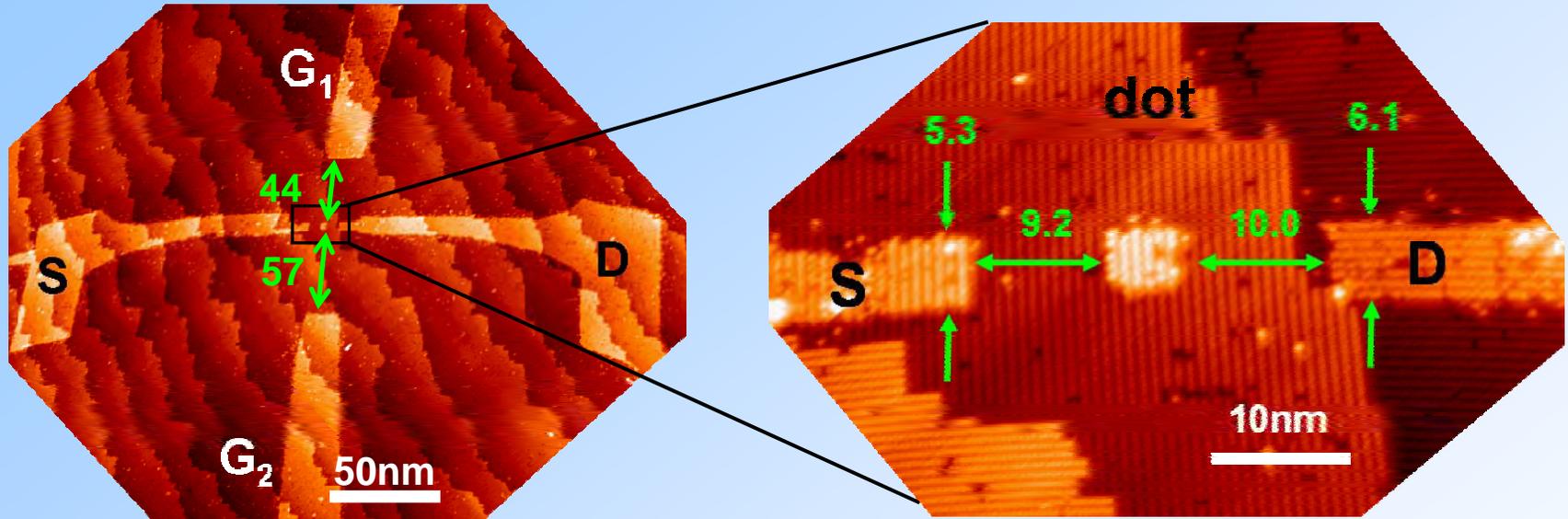


STM image of a quantum dot device



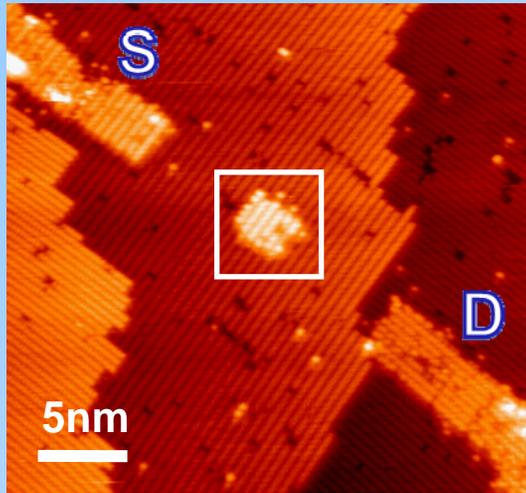
H desorbed regions appear brighter

Single crystal few-electron quantum dot

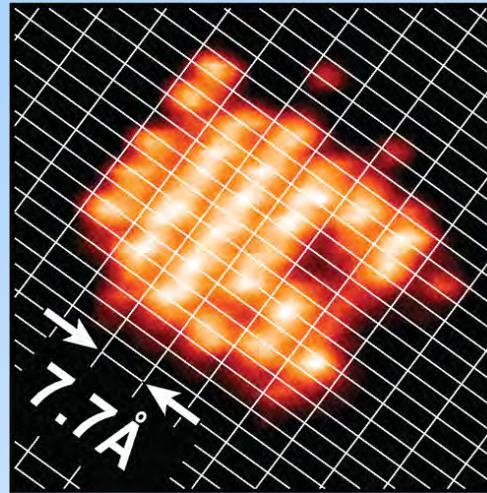


- 4 terminal quantum dot ($4.6 \times 4.6 \text{nm}^2$)
- S,D leads, quantum dot, and gates are planar, highly P doped silicon
- Fully epitaxial structure, avoiding interface and surface related challenges

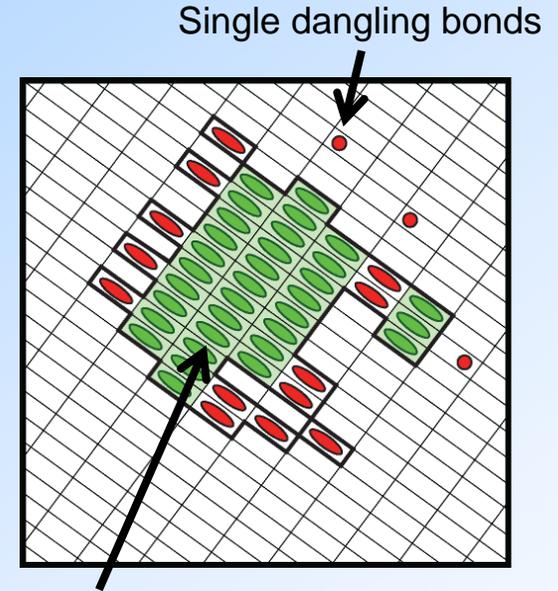
Accurate estimation of the number of donors



H lithography mask on Si(001)



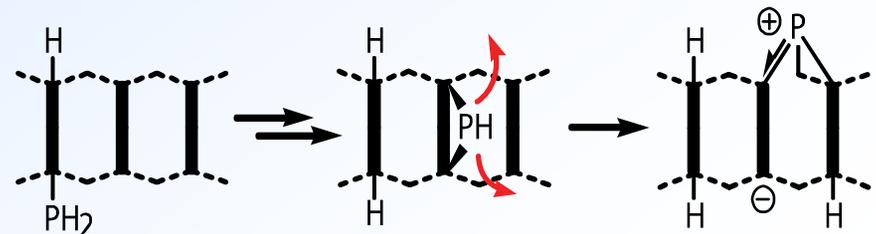
Overlay grid with dimer row spacing



Possible P incorporation sites

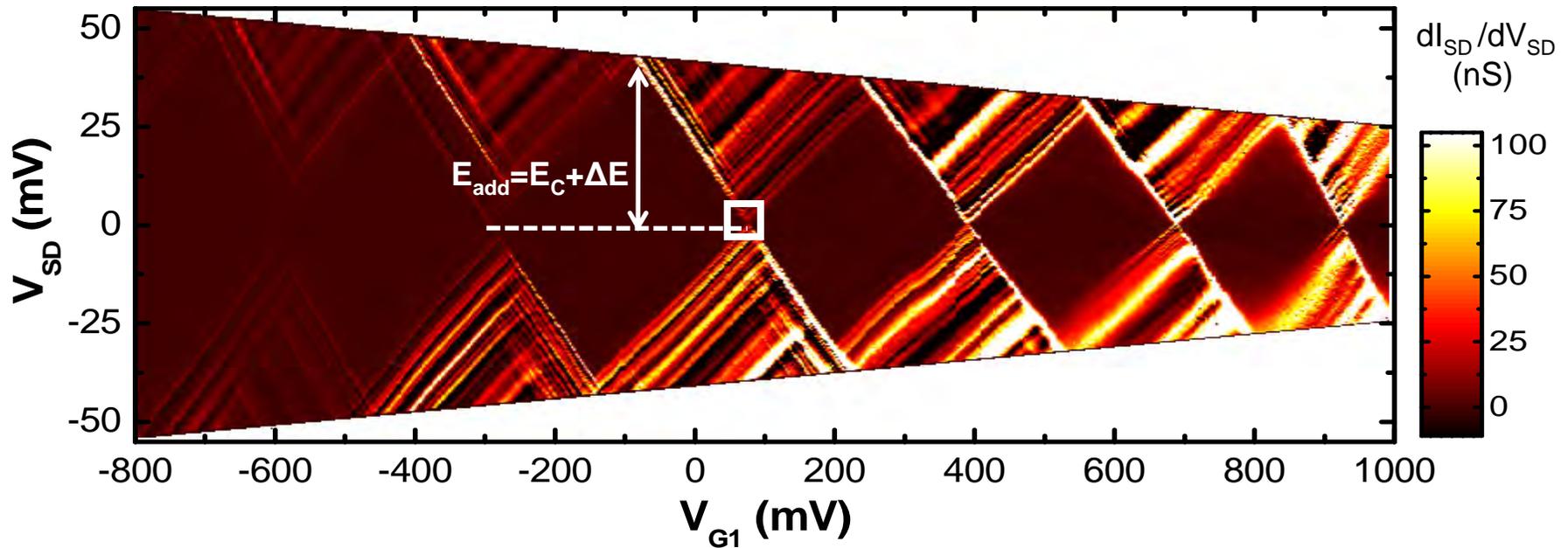
- STM allows for direct counting of H-desorbed Si dimers/adsorption sites
- Detailed P incorporation mechanism previously studied*:
→ 3 adjacent dimers are required for 1 P atom to incorporate

- Statistical incorporation study for similar dot sizes → **7 donors** most likely



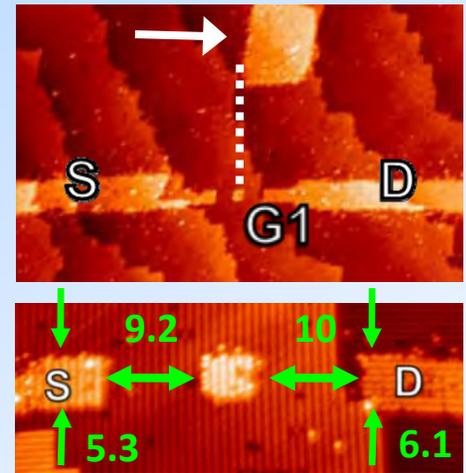
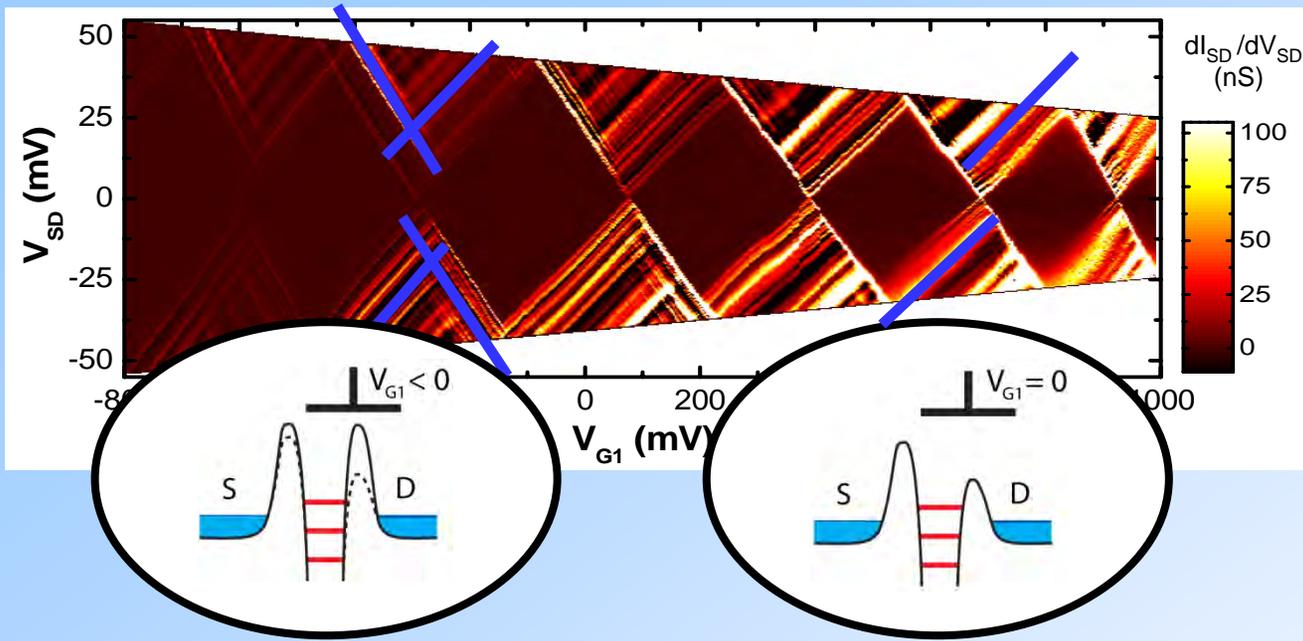
* S. R. Schofield, *et al.*, *Phys. Rev. Lett.* **91** (2003)
H. F. Wilson, *et al.*, *Phys. Rev. Lett.* **93** (2004)
O. Warschkow, *et al.*, *Phys. Rev. B* **72** (2005)

Stability Plot at mK temperatures



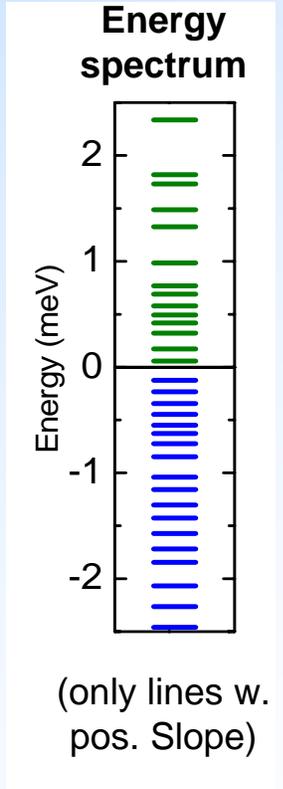
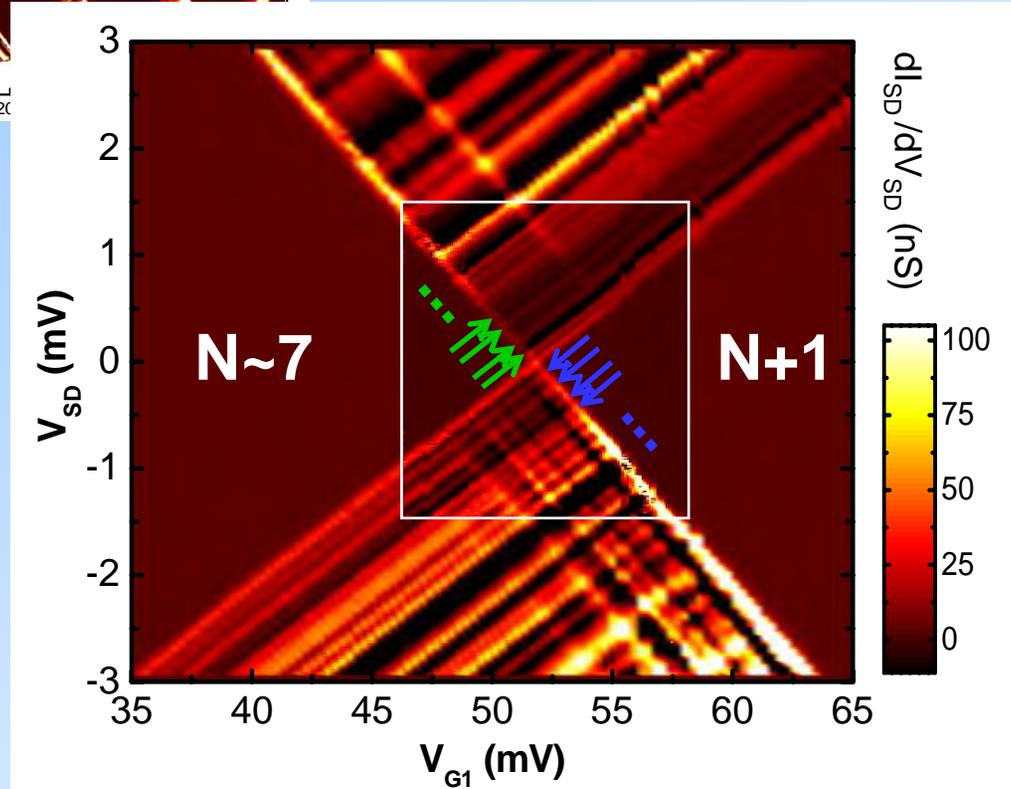
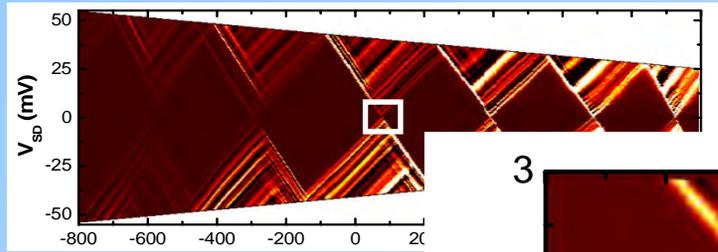
- Gate voltage dependence of tunnel barriers:
 - Increase in device conductance → change in coupling asymmetry
- Rise in addition energy as electron occupation is lowered → few-electron dot
- Surprisingly high density of lines of increased conductance
- Charge offset stability: $< 0.01e$ over two days (within 30mV gate window)

Control of dot barrier asymmetry



- $V_{G1} > 0$: we predominantly observe lines with positive slope
→ stronger *tunnel coupling* to D (higher gap aspect ratio: $0.61 > 0.58$)
- Gate G1 shifted towards D: coupling asymmetry changes with gate voltage

Surprisingly dense excitation spectrum



- Close-up of transition close to $V_G=0$ reveals even higher density of resonant features
- Average level spacing $\Delta E \sim 130\mu\text{eV}$

→ What is the origin of the resonant features?

Can these resonances be attributed to orbital excited states?

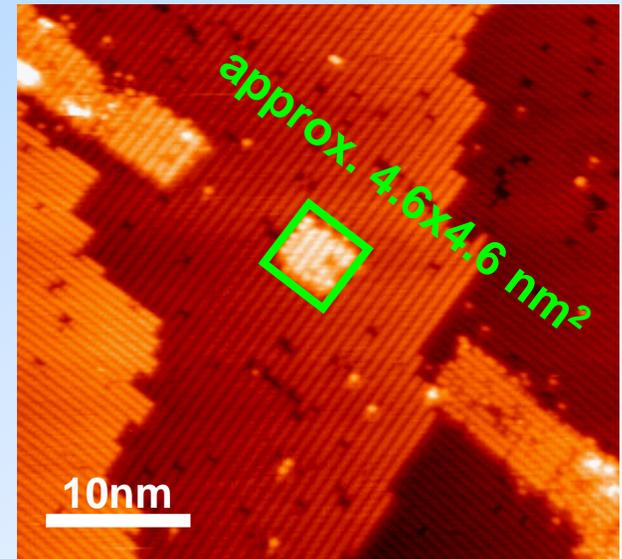
Estimate for the mean level spacing for laterally confined dots*:

$$\Delta E = \frac{\pi \hbar^2}{g m^* A}$$

→ Assume an effective mass $m_{\text{ave}}^* = 0.28 m_e$

→ Assume max. degeneracy factor $g = g_{\text{spin}} \times g_{\text{valley}} = 2 \times 6$

➔ $\Delta E \sim 12 \text{ meV}$



➔ The tight lateral confinement cannot account for the dense excitation spectrum

*L.P. Kouwenhoven *et al.*, *NATO Advanced Study Inst. on Mesos. Electron. Transp.* (1997)

[$m_{\text{ave}}^* = 0.28 m_e$ from G. Qian, *et al.*, *Phys. Rev. B* **71**, 045309 (2005)]

Can they be density-of-states fluctuations in the leads?

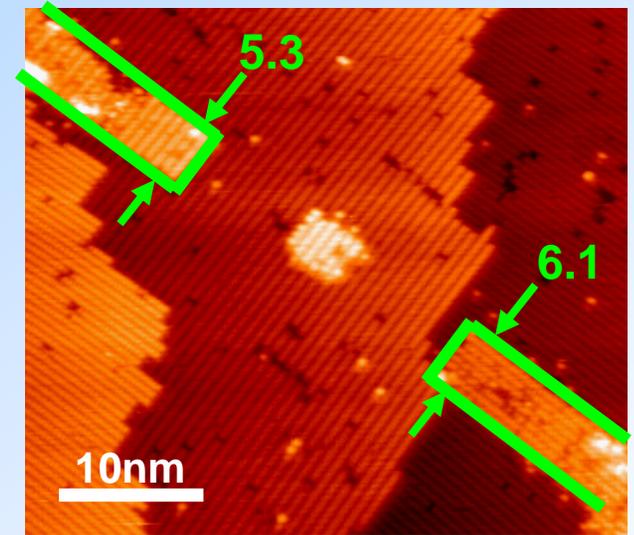
- Quasi 1D transport in narrow ($\sim 6\text{nm}$) S,D leads
→ Spacing of 1D subbands (for harmonic confinement)

$$\Delta E_n = \frac{\hbar\omega_0}{g} = \frac{\hbar}{g} \sqrt{\frac{8V}{m^*l^2}}$$

→ Assume $g=12$ and $m^*=0.28m_e$

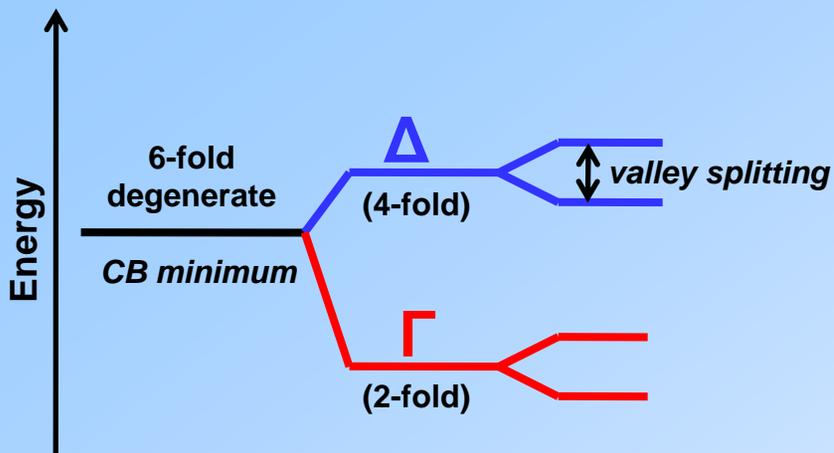
→ Assume barrier height $V=100\text{meV}$ (from detailed tunnel gap studies)

➔ $\Delta E_n \approx 7 \text{ meV}$

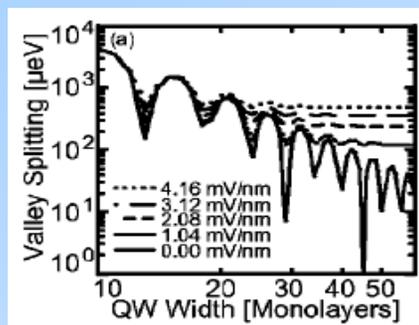
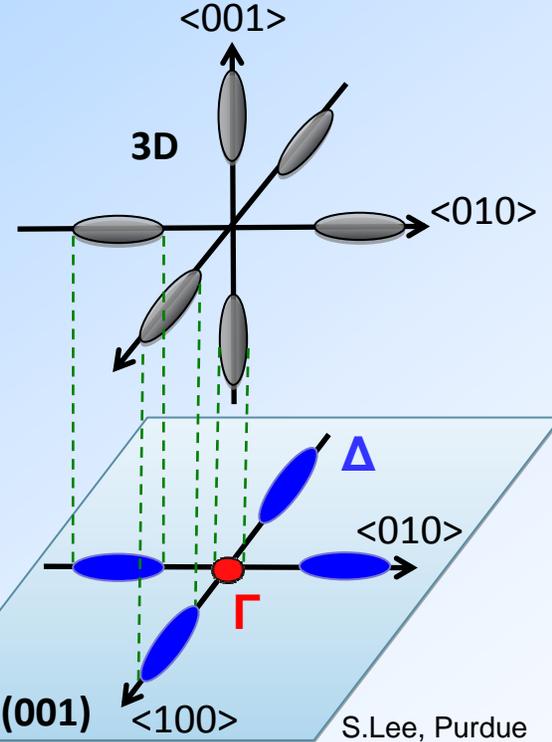


➔ The tight lateral confinement of the leads cannot account for the dense excitation spectrum

Valley splitting in silicon devices

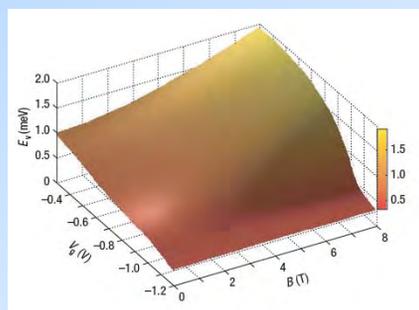


bulk Si:
6 degenerate valleys



Valley splitting
oscillates as a
function of well
width

T. B. Boykin, *et al.*, *Appl. Phys. Lett.* **84**, 115 (2004)

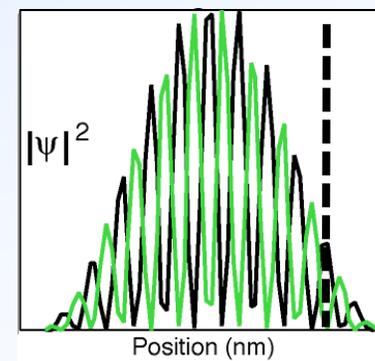


Valley splitting is
controllable via gate
voltage and B

S. Goswami, *et al.*, *Nat. Phys.* **3**, 41 (2007)

steep confinement, interfaces:

splitting of remaining degeneracy due to difference in fast oscillating part of the wave-functions

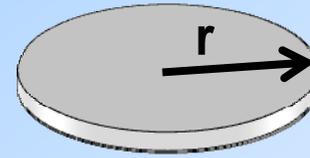
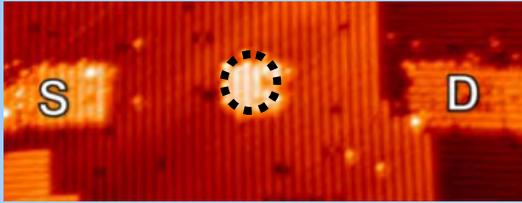


- valley splitting comparable in size to Zeeman splitting \rightarrow valley states vs. spin states
- valley degeneracy can be a source of decoherence

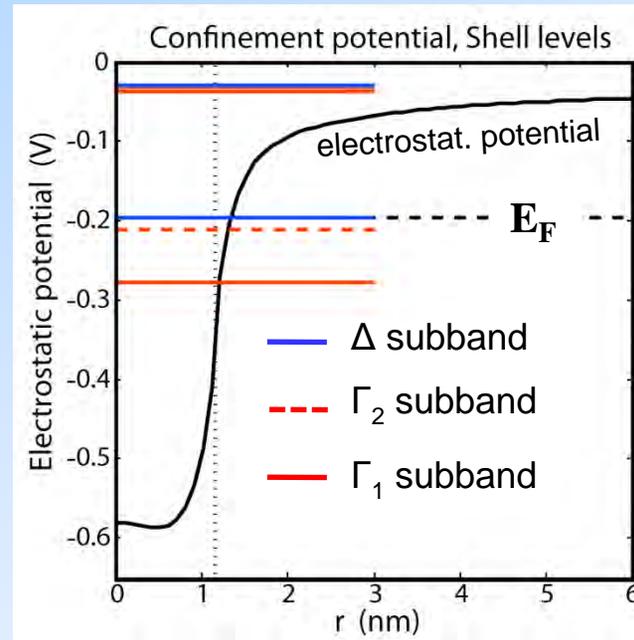
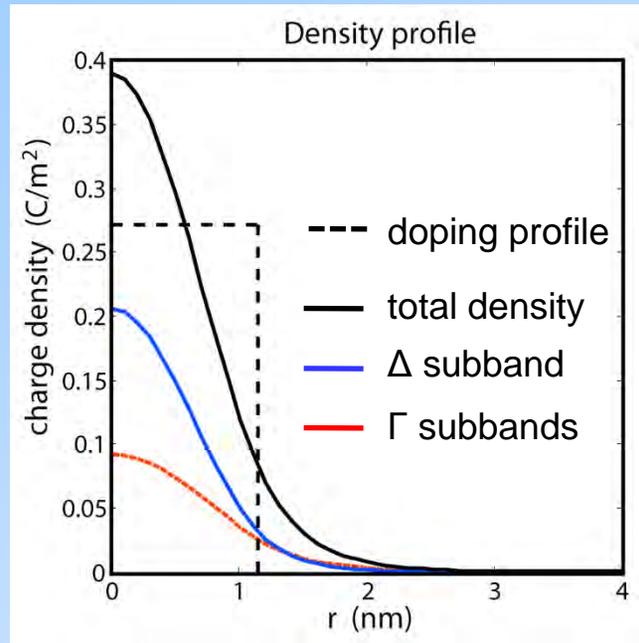
M. Friesen, *et al.*, *Phys. Rev. B* **75**, 115318 (2007)

B. Koiller, *et al.*, *Phys. Rev. Lett.* **88**, 027903 (2002)

Effective mass modelling of 7 donor dot

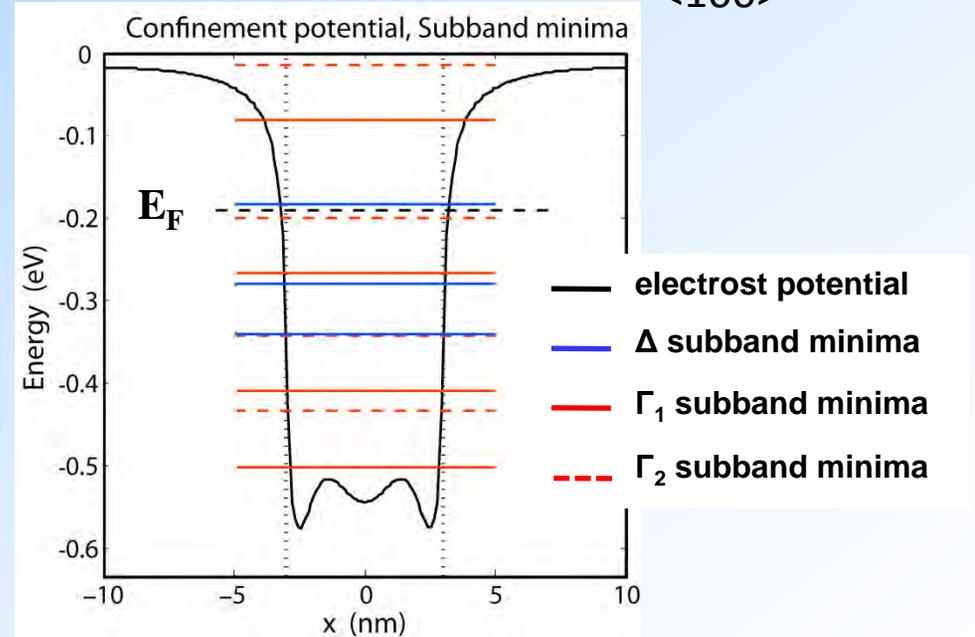
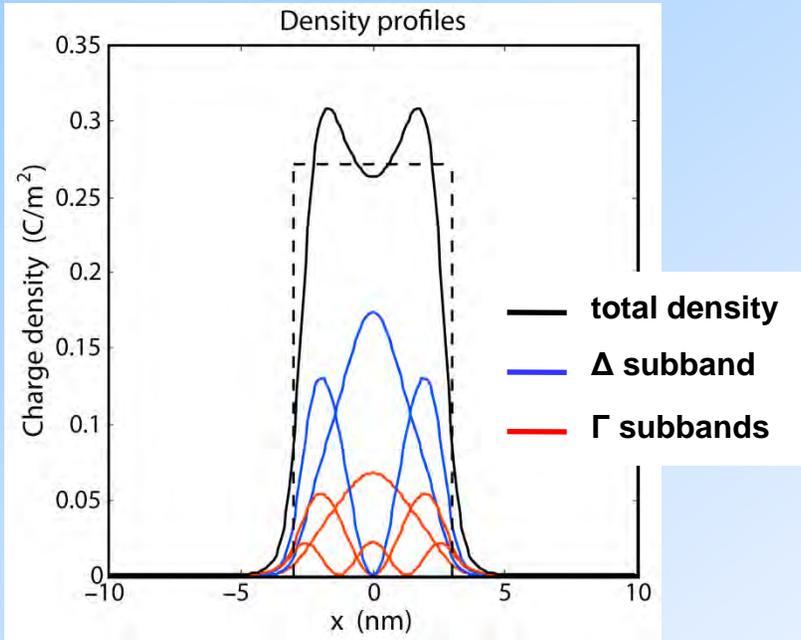
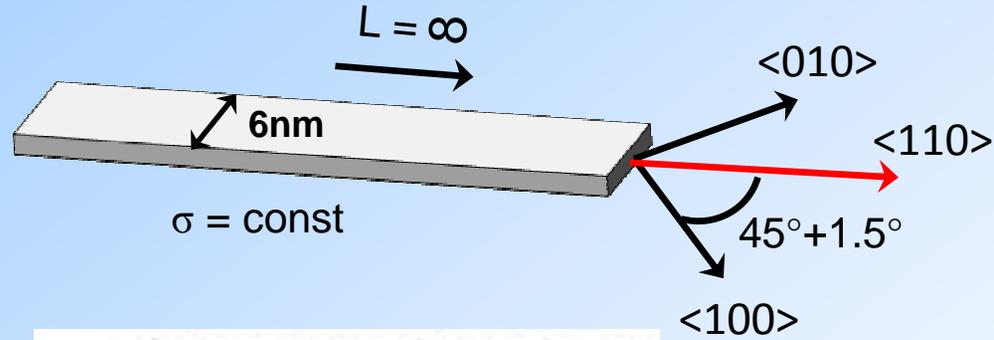
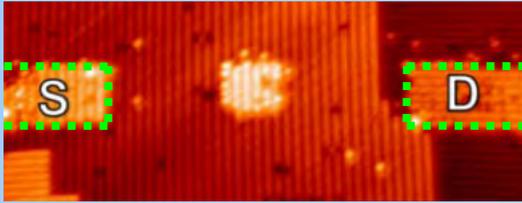


$$\sigma = \text{const}, r = 1.15 \text{ nm}$$



- Treat ions as 2D jellium of positive charge with circular symmetry
- Assume constant charge density from P δ -doped Si
- Self-consistently solve for charge density and energy levels using an effective mass approach

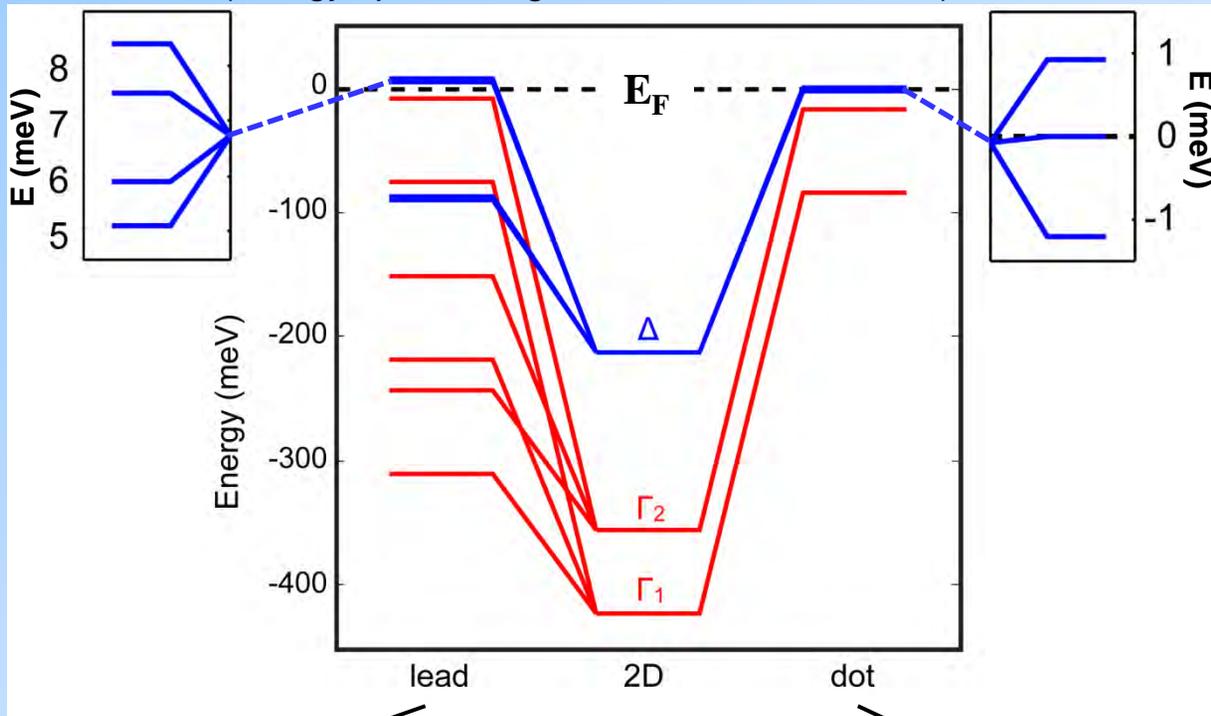
Modelling of 1D source and drain leads



- Treat source and drain leads as an infinite 6nm wide wire
- Assumed orientation of $45 + 1.5$ degrees from crystallographic $[100]$ axes

Comparison of 2D, 1D and 0D density of states in Si:P

(energy spectra aligned at their Fermi levels)



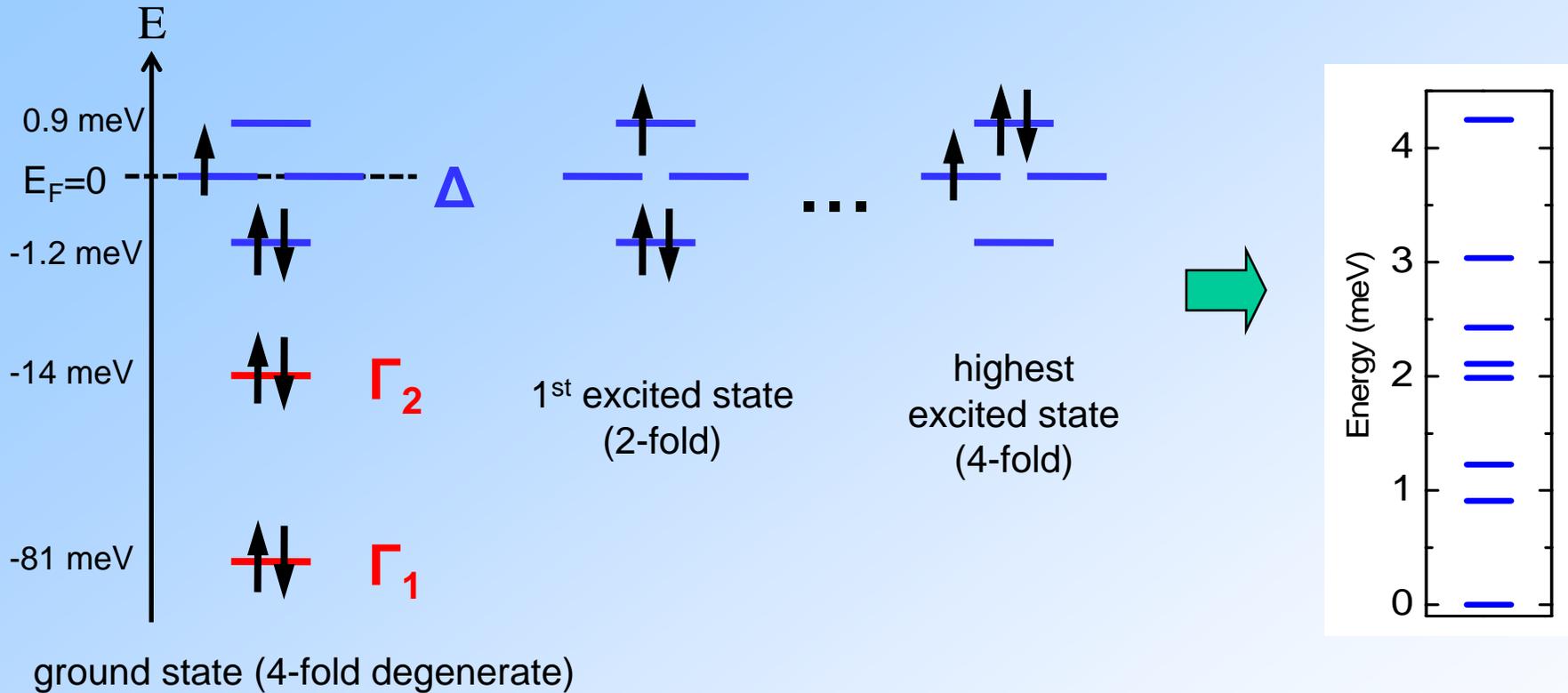
middle level 2-fold degenerate due to circular symmetry

Valley degeneracies lifted due to 1.5° misalignment from [110]

- Subband spacing on the order of 10s of meV
- It is unlikely that the valley split Δ states are aligned exactly at E_F to contribute to observed low-lying spectrum
- 3 “shells” occupied: Γ_1 , Γ_2 and Δ
- Valley splitting of Δ states on the order of 1meV at E_F

→ The observed spectrum at small bias voltages is due to electronic states in the leads

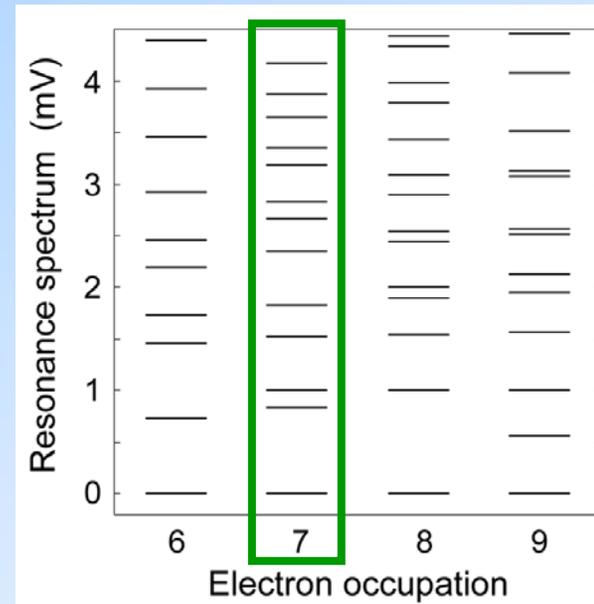
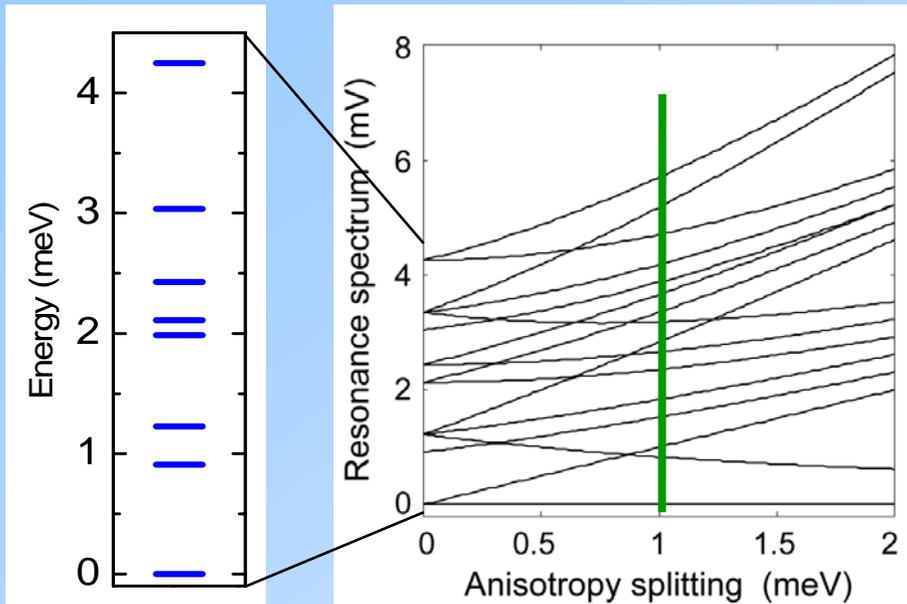
Calculated transport spectrum of a 7 donor symmetric dot



- For 3 electrons in Δ shell: there are 56 possible configurations with 8 different energies (2 to 16-fold degenerate)
- In addition, all levels are 2-fold spin degenerate

➔ For $N=7$: around zero bias there are 8 transport resonances within ~4 mV bias window

Realistic asymmetric dot: splitting of remaining degeneracy



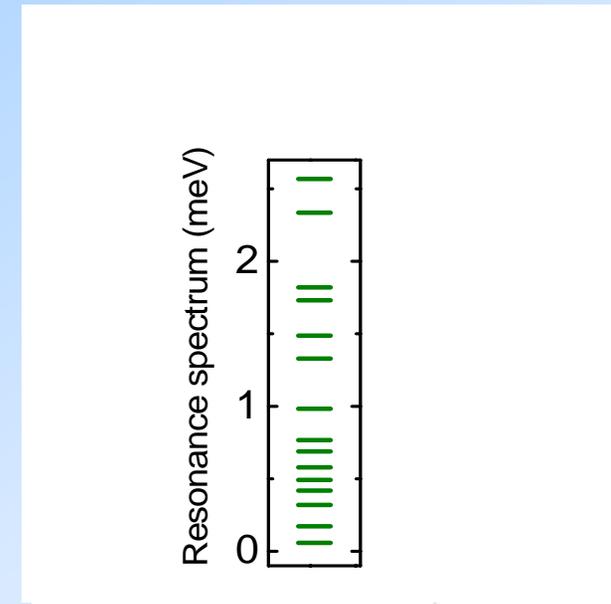
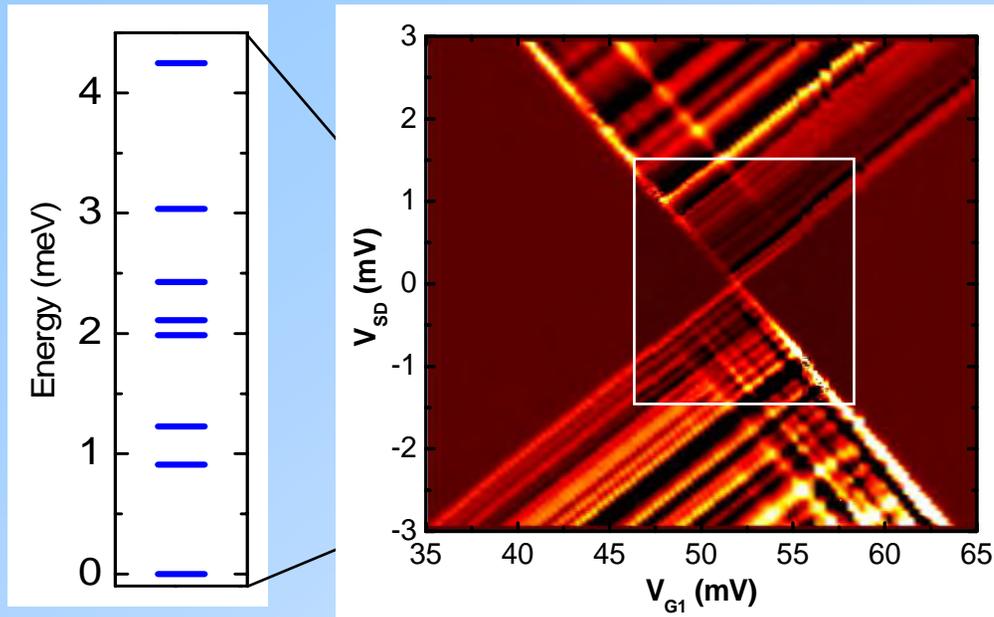
Modelling: avg. level spacing $\sim 300\mu\text{eV}$

- We use a perturbation approach to include dot anisotropy

- ➔ The remaining degeneracies are lifted (except for spin)
- ➔ Good qualitative agreement with the observed spectrum

➔ **The observed resonances are due to valley splitting in the quantum dot**

Realistic asymmetric dot: splitting of remaining degeneracy



Modelling: avg. level spacing $\sim 300\mu\text{eV}$

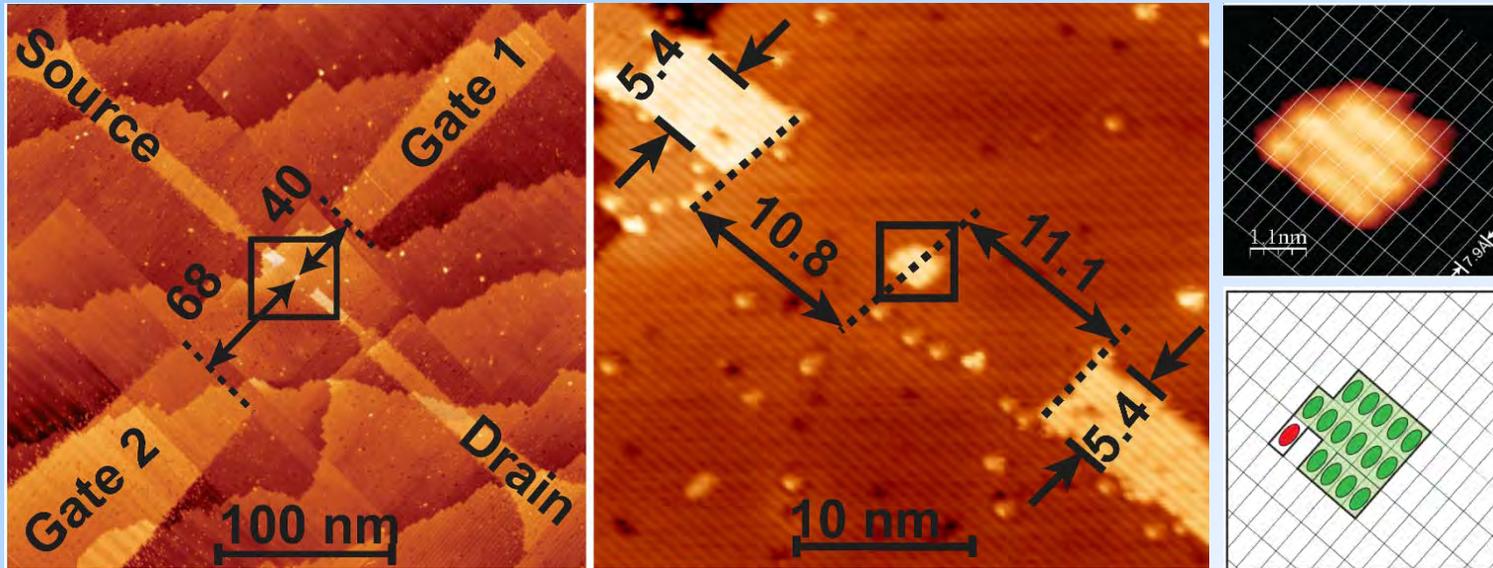
Experiment: avg. level spacing $\sim 100\mu\text{eV}$

- We use a perturbation approach to include dot anisotropy

- The remaining degeneracies are lifted (except for spin)
- Good qualitative agreement with the observed spectrum

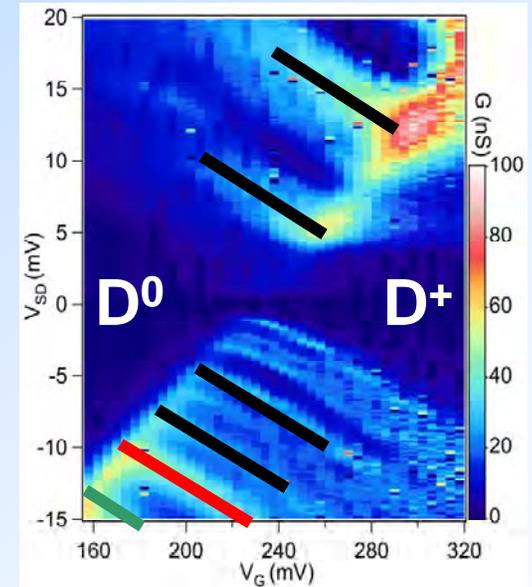
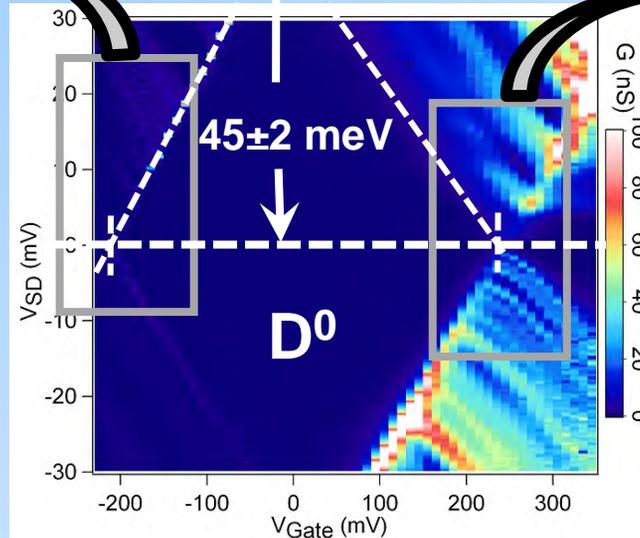
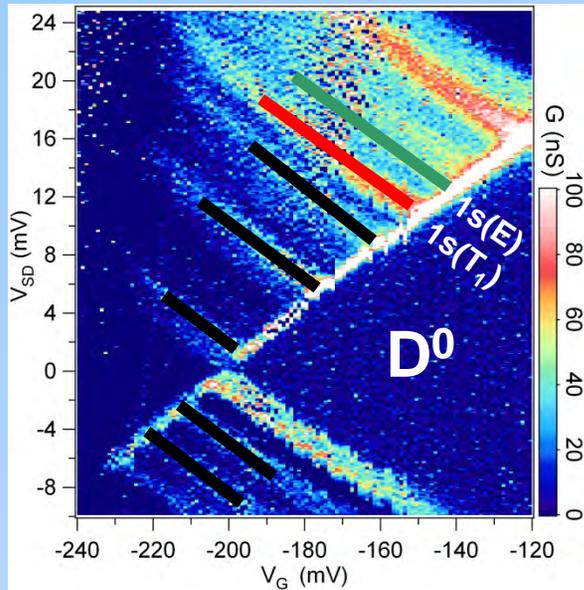
→ The observed resonances are due to valley splitting in the quantum dot

How does the valley splitting change in the single donor limit?

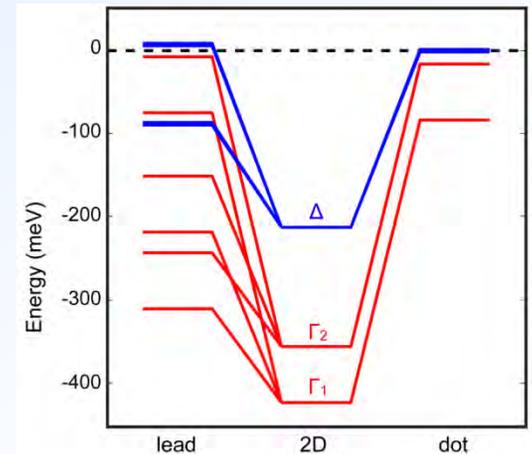


- We have a decreased the desorbed dot area ($1.7 \times 1.7 \text{ nm}^2$)
- From desorption statistics:
 - 1-3 donors most probable due to edge effects

Spectroscopy consistent with single donor

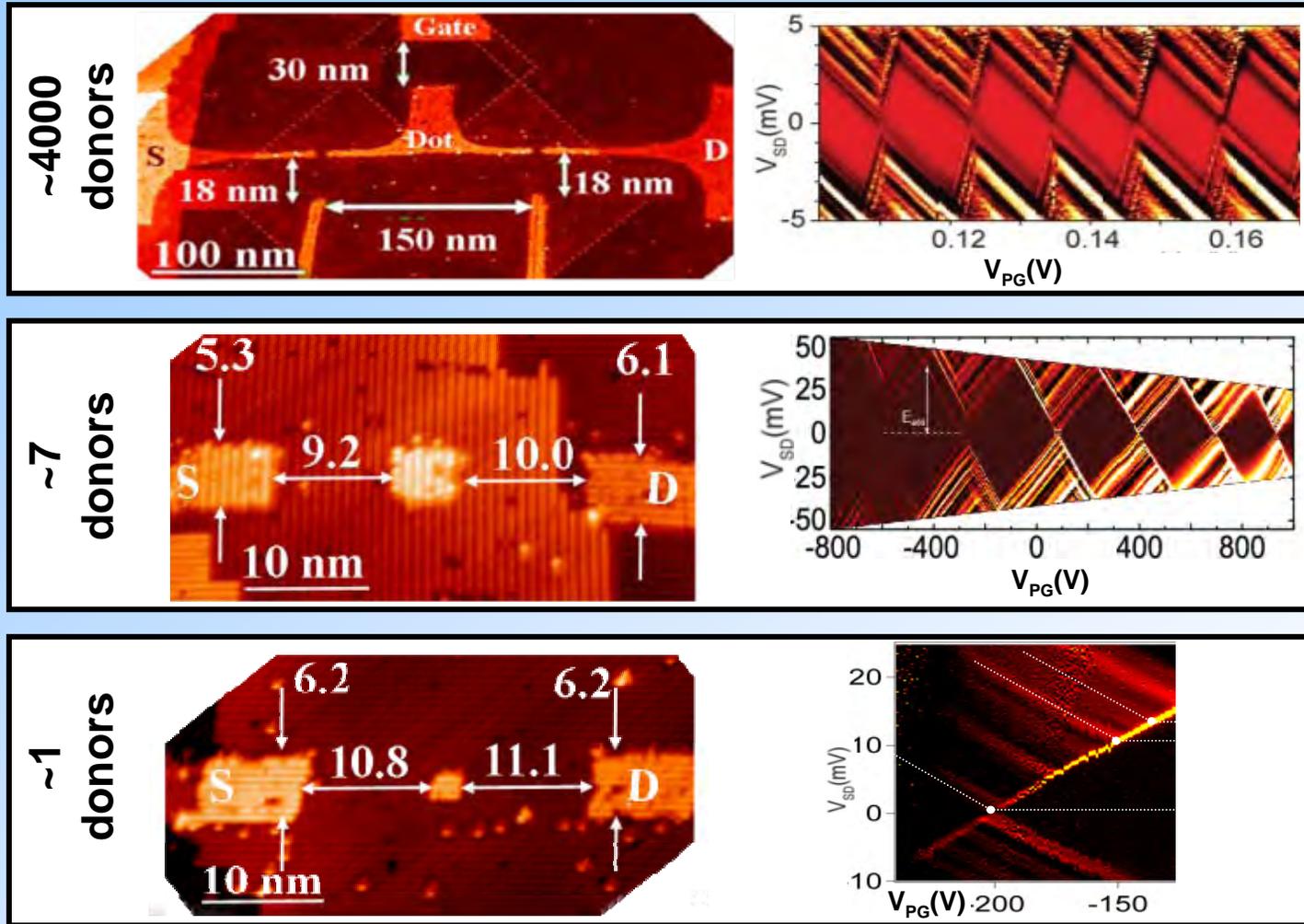


Excited States	1s(T1)	1s(E)
Bulk Si:P (mV)	11.70	13.01
(+)ve VG1 (mV)	10.4±2.8	13.8±1.4
(-)ve VG1 (mV)	10.8±1.3	13.9±1.4



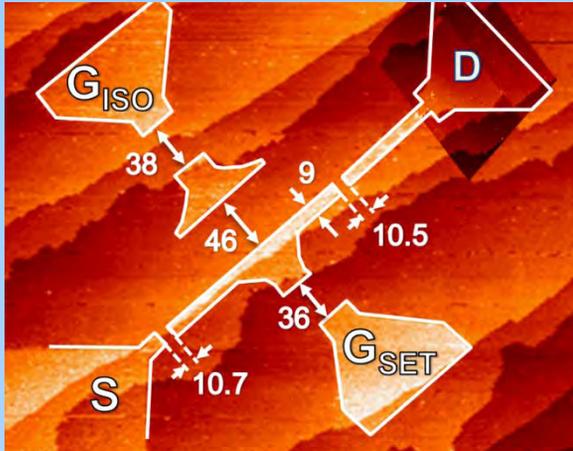
- The addition energy is consistent with the D^0 ground state of a P donor
- The excited state resonances are consistent with transitions of a single P donor in bulk Si (visible at either end of the D^0 diamond)
- Additional lines may be due to van Hove singularities of the leads

Valley splitting in donor based quantum dots

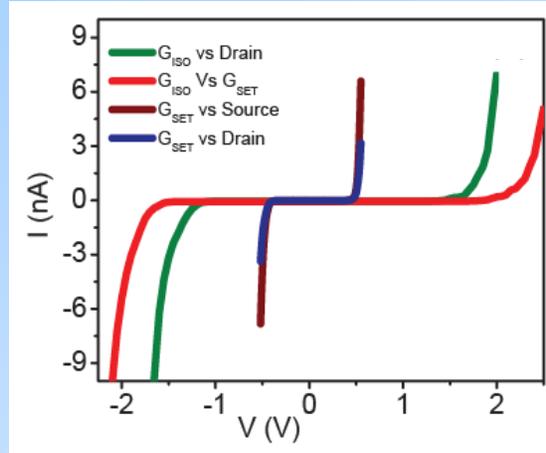


→ modeling provides consistent explanation for all transport resonances observed

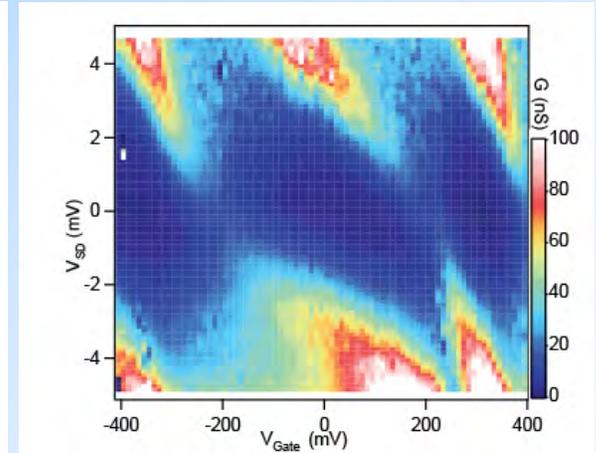
Towards charge detection in an in-plane architecture



parallel double dot structure



gate leakages

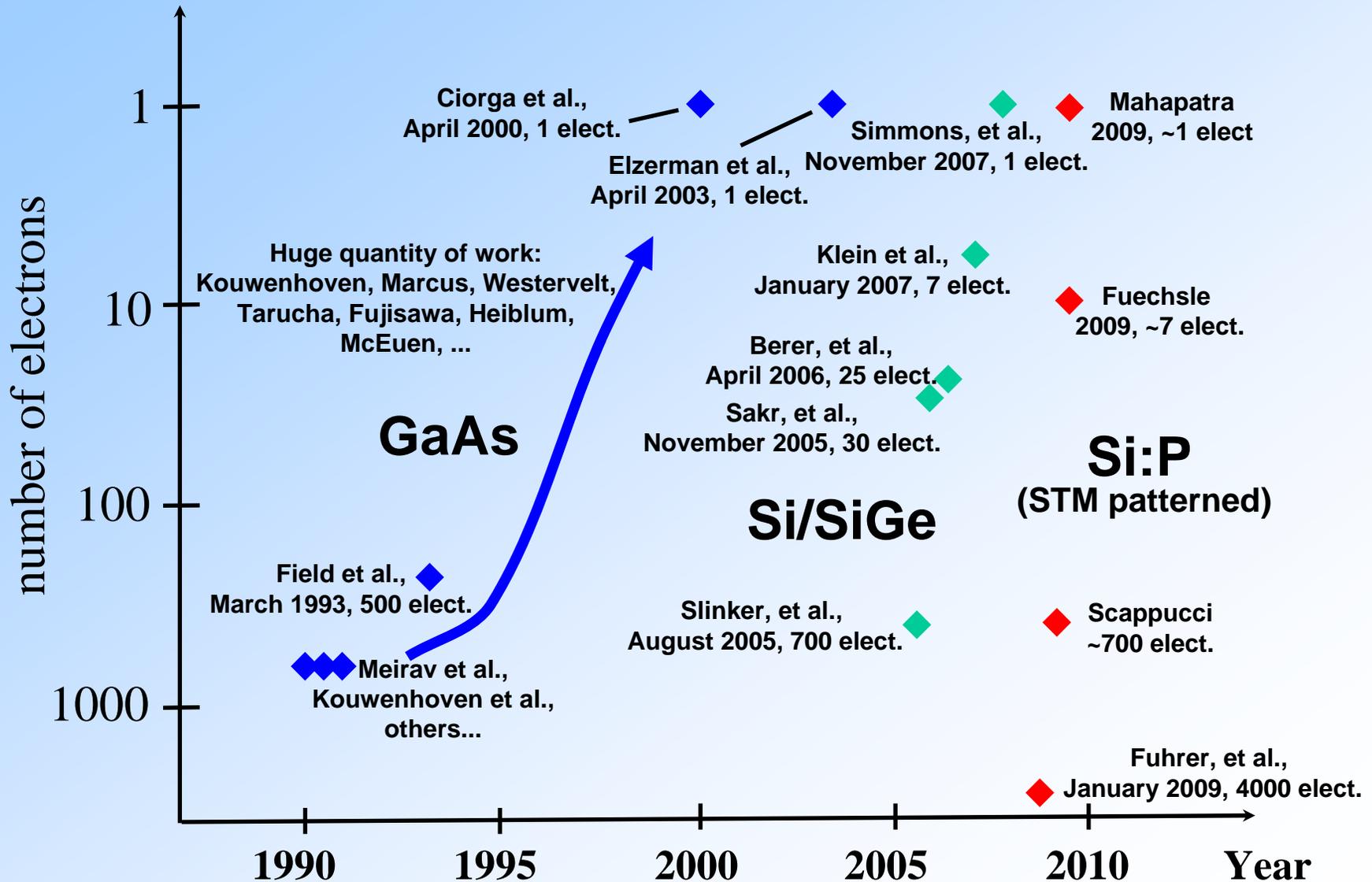


stability diagram of SET dot at 4K

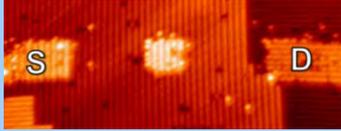
- We demonstrate the ability to pattern a second quantum dot as a SET detector
 - The gating ranges match with device design
 - The SET charging energy is in agreement with FastCap calculations ($\leq 5\text{meV}$)
- ➔ Further optimization of the device design is necessary

Number of electrons in gated quantum dots

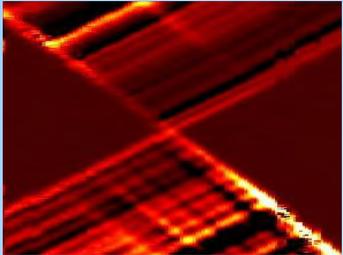
(courtesy of M. Eriksson)



Summary

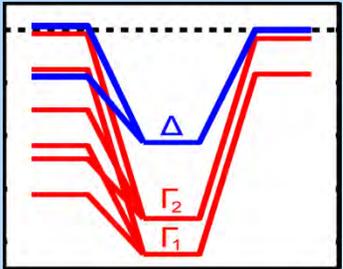


- We have decreased the number of donors from 4000 to ~ 1



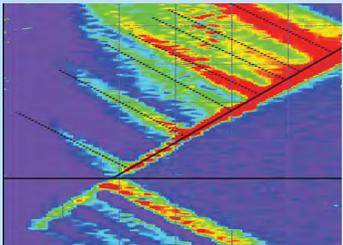
- Valley splitting leads to a dense excitation spectrum in a 7 donor based quantum dot with an energy of $100\mu\text{eV}$

- This splitting is reduced at the level of single donors.



- Effective mass theory provides an efficient means to analyze complex donor structures in silicon

- Strategies underway to control valley splitting: using lower carrier densities and strain.



- We have demonstrated the integration of a second dot towards the goal of an in-plane charge sensor